Abstracts

A new dynamic load-line measurement method with EOS and load-pull system for power FET design

H. Takahashi and M. Kanamori. "A new dynamic load-line measurement method with EOS and load-pull system for power FET design." 1999 MTT-S International Microwave Symposium Digest 99.4 (1999 Vol. IV [MWSYM]): 1651-1654 vol.4.

We have developed a new dynamic load-line measurement method with EOS (electro-optic sampling) and load-pull systems, and demonstrated the accuracy of this measurement method using a MESFET under large signal operation (Wg=1.2 mm, f=2 GHz). This method is highly suitable for the design and verification of matching circuits for power FET's and MMIC's.

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